

O I P E
FEB 17 2005
JC73
U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

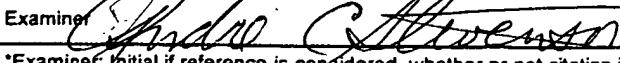
SHEET 1 OF 1

Form PTO 1449 (Modified)		ATTY DOCKET NO. 241677US2	SERIAL NO. 10/642,222				
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT Kenji YOSHIDA, et al.					
		FILING DATE August 18, 2003	GROUP 2812				
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
AA							
AB							
AC							
AD							
AE							
AF							
AG							
AH							
AI							
AJ							
AK							
AL							
AM							
AN							
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
		AO 10-12687	01/16/1998	JAPAN	YES	NO	X
		AP 3-254126	11/13/1991	JAPAN			X
		AQ					
		AR					
		AS					
		AT					
		AU					
		AV					
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
		AW					
		AX					
		AY					
		AZ					
					<input type="checkbox"/> Additional References sheet(s) attached		
Examiner					Date Considered 05/11/06		

* Examiner initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



SHEET 1 OF 1

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 241677US2	SERIAL NO. 10/642,222		
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT Kenji YOSHIDA, et al.					
		FILING DATE August 18, 2003		GROUP 2812			
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
CD	AA	5,930,587	07/27/1999	V. W. RYAN			
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
					YES	NO	
	AO						
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW	K. YOSHIDA, et al., International Electron Device Meeting, pages 753-756, "STRESS-INDUCED VOIDING PHENOMENA FOR AN AACTURAL CMOS LSI INTERCONNECTS", December 2002					
	AX						
	AY						
	AZ						
		<input type="checkbox"/> Additional References sheet(s) attached					
Examiner			Date Considered <u>05/11/06</u>				
*Examiner Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							